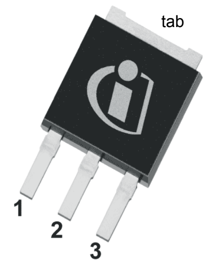
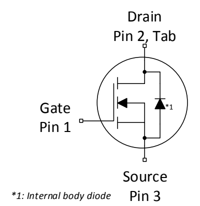
MOSFET

600V CoolMOS™ PFD7 SJ Power Device

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies.
The latest CoolMOS™ PFD7 is an optimized platform tailored to target cost sensitive applications in consumer markets such as charger, adapter, motor drive, lighting, etc.
The new series provides all the benefits of a fast switching Superjunction MOSFET, combined with an excellent price/performance ratio and state of the art ease-of-use level. The technology meets highest efficiency standards and supports high power density, enabling customers going towards very slim designs.

IPAK SL





Features

- Extremely low losses due to very low FOM $R_{DS(on)}$*Q_g and $R_{DS(on)}$*E_{oss}
- Low switching losses E_{oss}, excellent thermal behavior
- Fast body diode
- Wide range portfolio of $R_{DS(on)}$ and package variations

Benefits

- Enables high power density designs and small form factors
- Enables efficiency gains at higher switching frequencies
- Excellent commutation ruggedness
- Easy to select right parts and optimize the design

Potential applications

Recommended for ZVS topologies used in high density chargers, adapters, lighting and motor drives applications, etc.

Product validation

Qualified according to JEDEC Standard

Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.

Table 1 Key Performance Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j,max}$	650	V
$R_{DS(on),max}$	210	mΩ
$Q_{g,typ}$	23	nC
$I_{D,pulse}$	42	A
E_{oss} @ 400V	2.6	µJ
Body diode di_F/dt	1300	A/µs
ESD Class (HBM)	1C	-

Type / Ordering Code	Package	Marking	Related Links
IPS60R210PFD7S	PG-TO 251-3	60S210D7	see Appendix A

Table of Contents

1 Maximum ratings

at T_j = 25°C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current[1]	I_D	- -	- -	16 10	A	T_C=25°C T_C=100°C
Pulsed drain current[2]	$I_{D,pulse}$	-	-	42	A	T_C=25°C
Avalanche energy, single pulse	E_{AS}	-	-	49	mJ	I_D=3.2A; V_{DD}=50V; see table 10
Avalanche energy, repetitive	E_{AR}	-	-	0.24	mJ	I_D=3.2A; V_{DD}=50V; see table 10
Avalanche current, single pulse	I_{AS}	-	-	3.2	A	-
MOSFET dv/dt ruggedness	dv/dt	-	-	120	V/ns	V_{DS}=0...400V
Gate source voltage (static)	V_{GS}	-20	-	20	V	static;
Gate source voltage (dynamic)	V_{GS}	-30	-	30	V	AC (f>1 Hz)
Power dissipation	P_{tot}	-	-	64	W	T_C=25°C
Storage temperature	T_{stg}	-40	-	150	°C	-
Operating junction temperature	T_j	-40	-	150	°C	-
Mounting torque	-	-	-	-	Ncm	-
Continuous diode forward current	I_S	-	-	16	A	T_C=25°C
Diode pulse current[2]	$I_{S,pulse}$	-	-	42	A	T_C=25°C
Reverse diode dv/dt[3]	dv/dt	-	-	70	V/ns	V_{DS}=0...400V, I_{SD}<=12A, T_j=25°C see table 8
Maximum diode commutation speed	di_F/dt	-	-	1300	A/µs	V_{DS}=0...400V, I_{SD}<=12A, T_j=25°C see table 8
Insulation withstand voltage	V_{ISO}	-	-	n.a.	V	V_{rms}, T_C=25°C, t=1min

[1] Limited by $T_{j,max}$. Maximum Duty Cycle D = 0.50
[2] Pulse width t_p limited by $T_{j,max}$
[3] Identical low side and high side switch with identical R_G

2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	1.94	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	leaded
Thermal resistance, junction - ambient for SMD version	R_{thJA}	-	-	-	°C/W	n.a.
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

3 Electrical characteristics

at T_j=25°C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	600	-	-	V	V_{GS}=0V, I_D=1mA
Gate threshold voltage	$V_{(GS)th}$	3.5	4	4.5	V	V_{DS}=V_{GS}, I_D=0.24mA
Zero gate voltage drain current[1]	I_{DSS}	- -	- 5	1 37	µA	V_{DS}=600V, V_{GS}=0V, T_j=25°C V_{DS}=600V, V_{GS}=0V, T_j=125°C
Gate-source leakage current	I_{GSS}	-	-	100	nA	V_{GS}=20V, V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	- -	0.171 0.386	0.210 -	Ω	V_{GS}=10V, I_D=4.9A, T_j=25°C V_{GS}=10V, I_D=4.9A, T_j=150°C
Gate resistance	R_G	-	11.0	-	Ω	f=1MHz, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	1015	-	pF	V_{GS}=0V, V_{DS}=400V, f=250kHz
Output capacitance	C_{oss}	-	18	-	pF	V_{GS}=0V, V_{DS}=400V, f=250kHz
Effective output capacitance, energy related[2]	$C_{o(er)}$	-	33	-	pF	V_{GS}=0V, V_{DS}=0...400V
Effective output capacitance, time related[3]	$C_{o(tr)}$	-	330	-	pF	I_D=constant, V_{GS}=0V, V_{DS}=0...400V
Turn-on delay time	$t_{d(on)}$	-	20	-	ns	V_{DD}=400V, V_{GS}=10V, I_D=4.9A, R_G=10.2Ω; see table 9
Rise time	t_r	-	16	-	ns	V_{DD}=400V, V_{GS}=10V, I_D=4.9A, R_G=10.2Ω; see table 9
Turn-off delay time	$t_{d(off)}$	-	57	-	ns	V_{DD}=400V, V_{GS}=10V, I_D=4.9A, R_G=10.2Ω; see table 9
Fall time	t_f	-	7	-	ns	V_{DD}=400V, V_{GS}=10V, I_D=4.9A, R_G=10.2Ω; see table 9

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	6	-	nC	V_{DD}=400V, I_D=4.9A, V_{GS}=0 to 10V
Gate to drain charge	Q_{gd}	-	7	-	nC	V_{DD}=400V, I_D=4.9A, V_{GS}=0 to 10V
Gate charge total	Q_g	-	23	-	nC	V_{DD}=400V, I_D=4.9A, V_{GS}=0 to 10V
Gate plateau voltage	$V_{plateau}$	-	5.7	-	V	V_{DD}=400V, I_D=4.9A, V_{GS}=0 to 10V

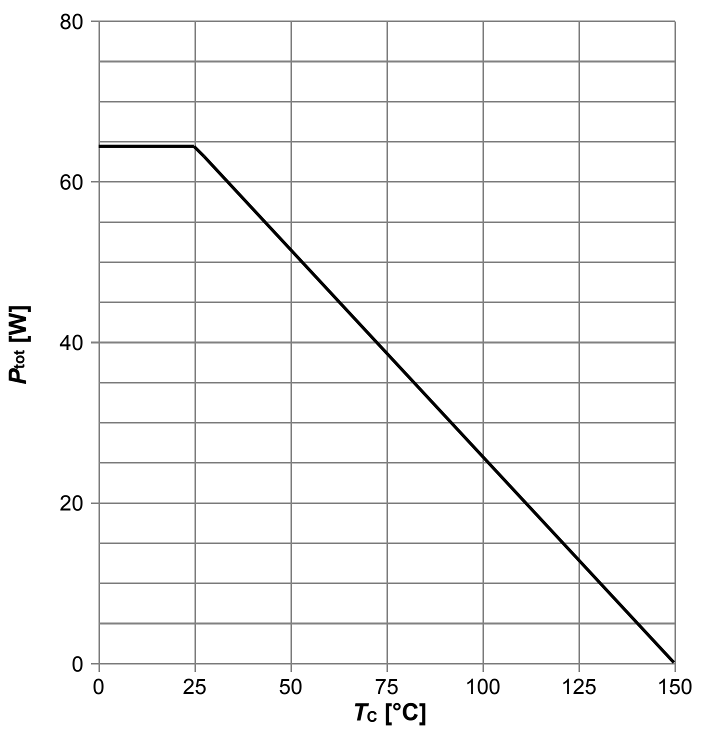
[1] Maximum specification is defined by calculated six sigma upper confidence bound
[2] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V
[3] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	1.0	-	V	V_{GS}=0V, I_F=4.9A, T_j=25°C
Reverse recovery time	t_{rr}	-	87	174	ns	V_R=400V, I_F=4.9A, di_F/dt=100A/µs; see table 8
Reverse recovery charge	Q_{rr}	-	0.34	0.68	µC	V_R=400V, I_F=4.9A, di_F/dt=100A/µs; see table 8
Peak reverse recovery current	I_{rrm}	-	6.8	-	A	V_R=400V, I_F=4.9A, di_F/dt=100A/µs; see table 8

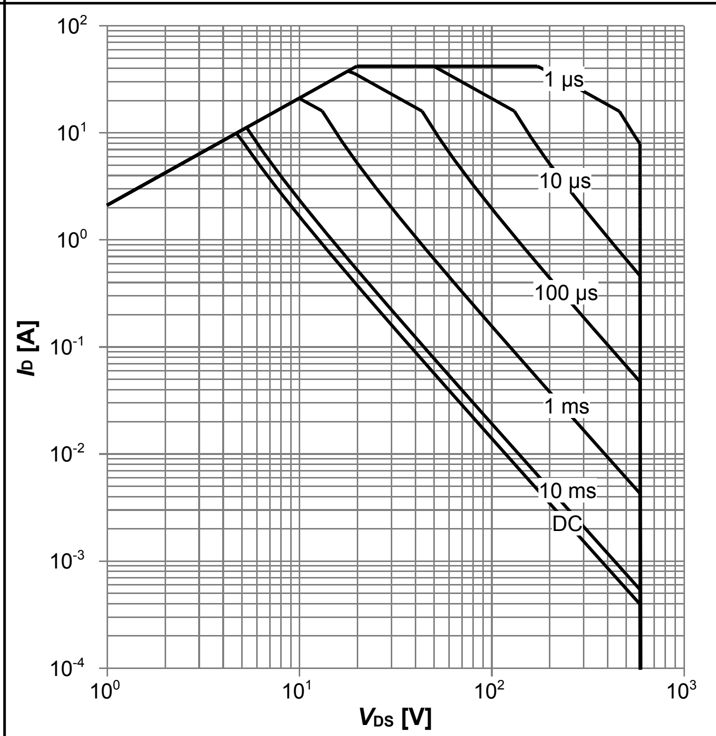
4 Electrical characteristics diagrams

Diagram 1: Power dissipation



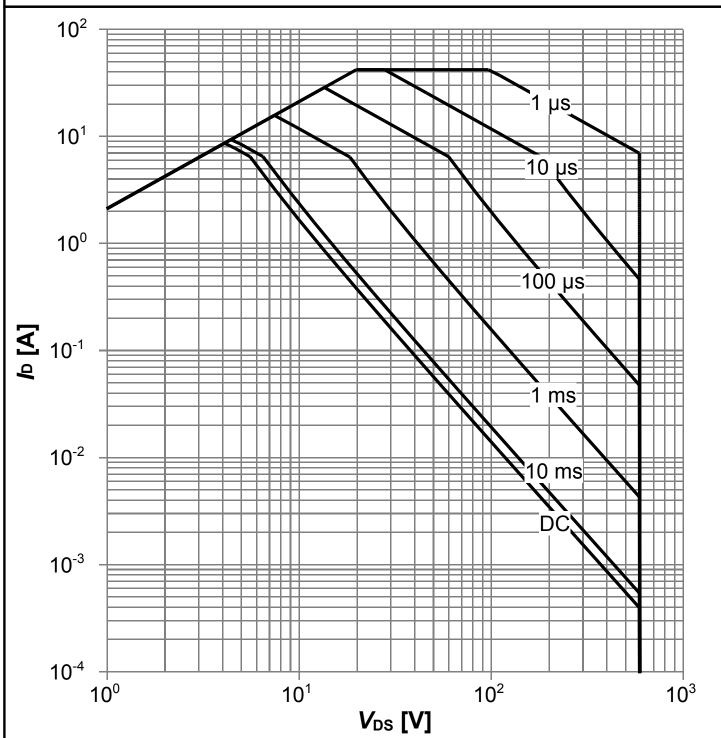
P_{tot}=f(T_C)

Diagram 2: Safe operating area



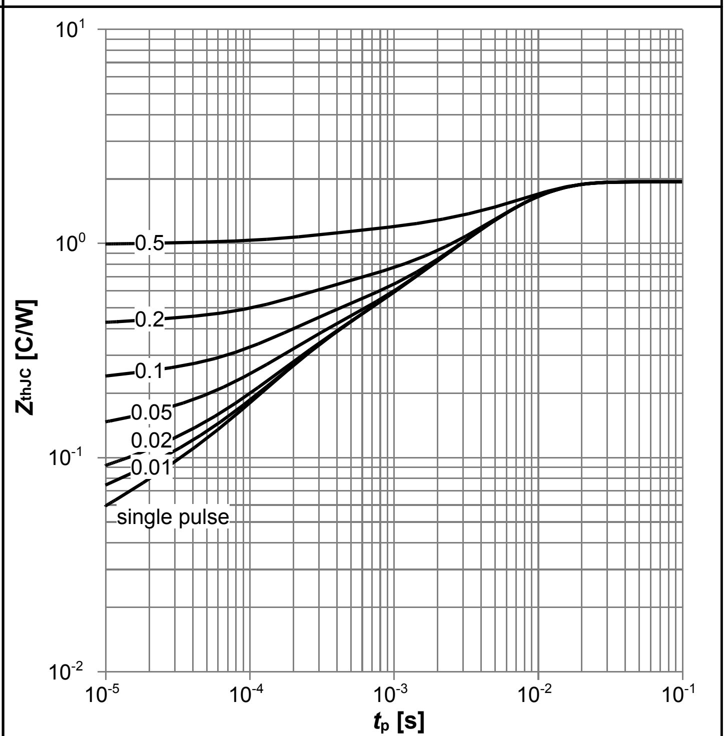
I_D=f(V_{DS}); T_C=25 °C; D=0; parameter: t_p

Diagram 3: Safe operating area



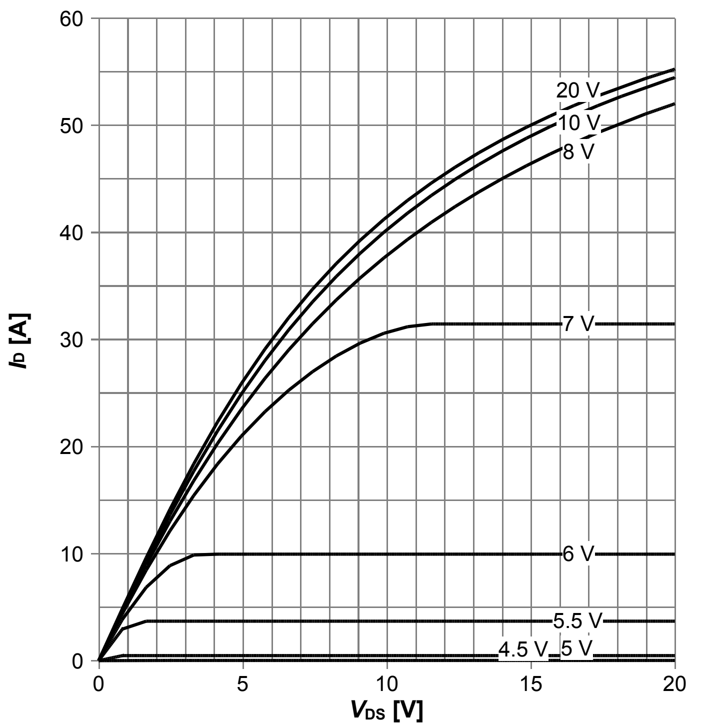
I_D=f(V_{DS}); T_C=80 °C; D=0; parameter: t_p

Diagram 4: Max. transient thermal impedance



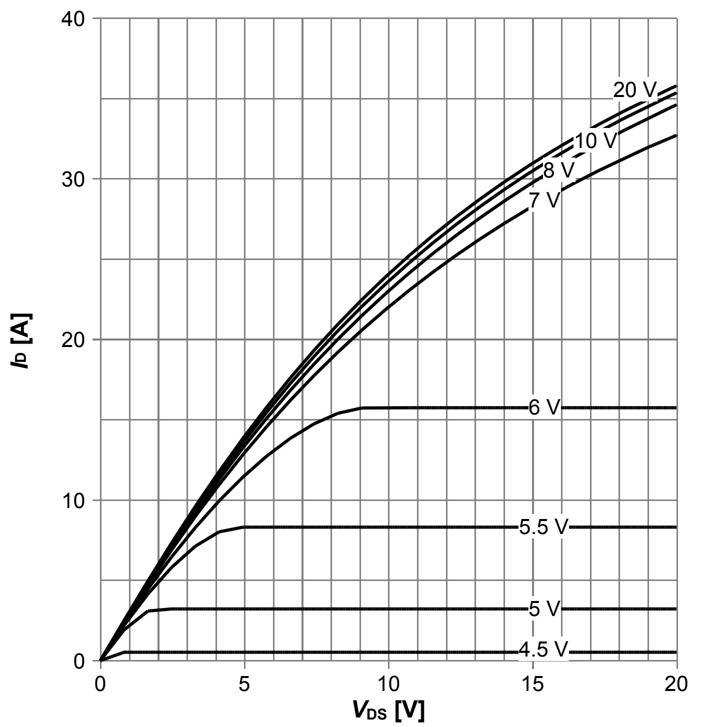
Z_{thJC} =f(t_P); parameter: D=t_p/T

Diagram 5: Typ. output characteristics



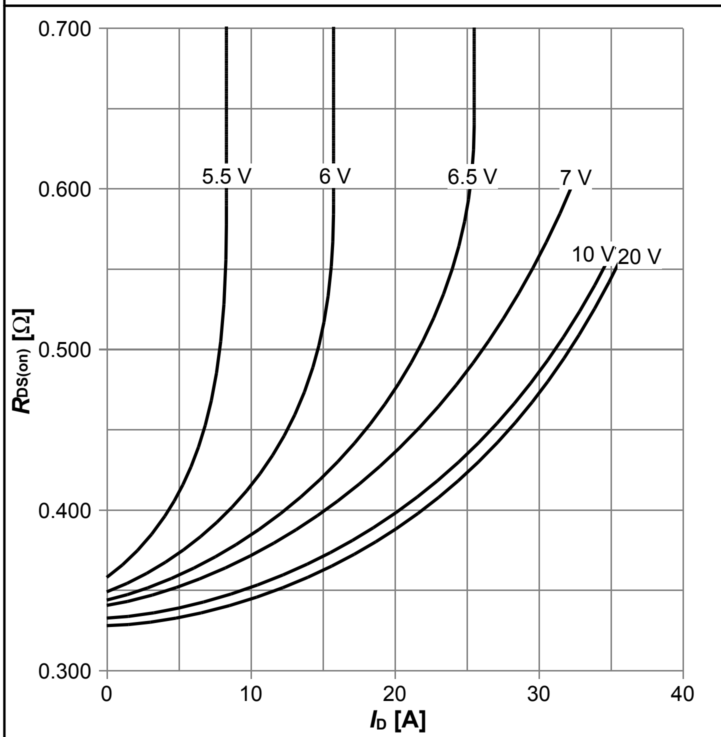
I_D=f(V_{DS}); T_j=25 °C; parameter: V_{GS}

Diagram 6: Typ. output characteristics



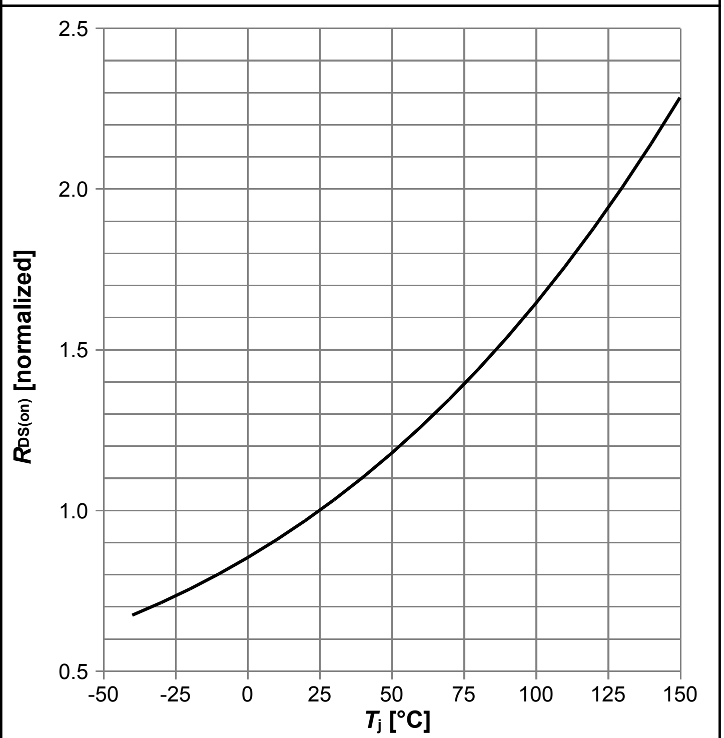
I_D=f(V_{DS}); T_j=125 °C; parameter: V_{GS}

Diagram 7: Typ. drain-source on-state resistance



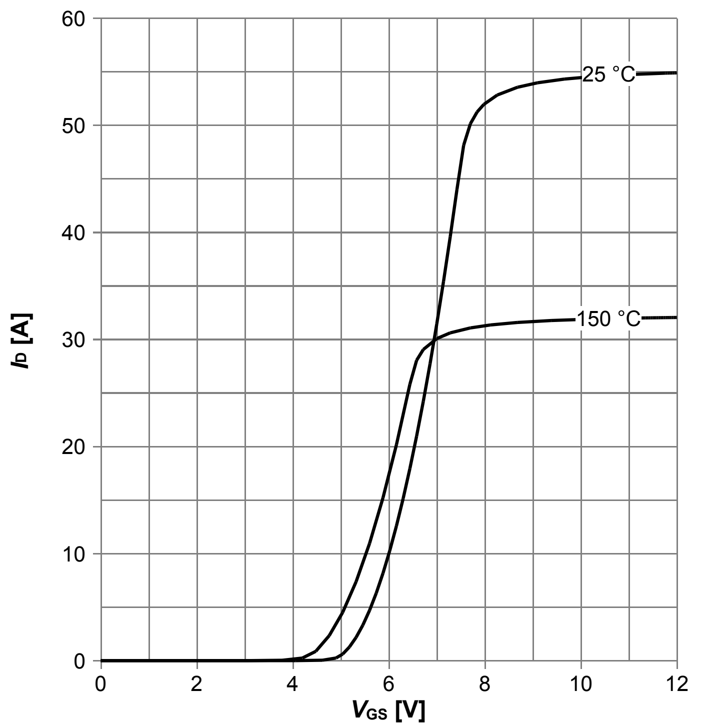
$R_{DS(on)}$=f(I_D); T_j=125 °C; parameter: V_{GS}

Diagram 8: Drain-source on-state resistance



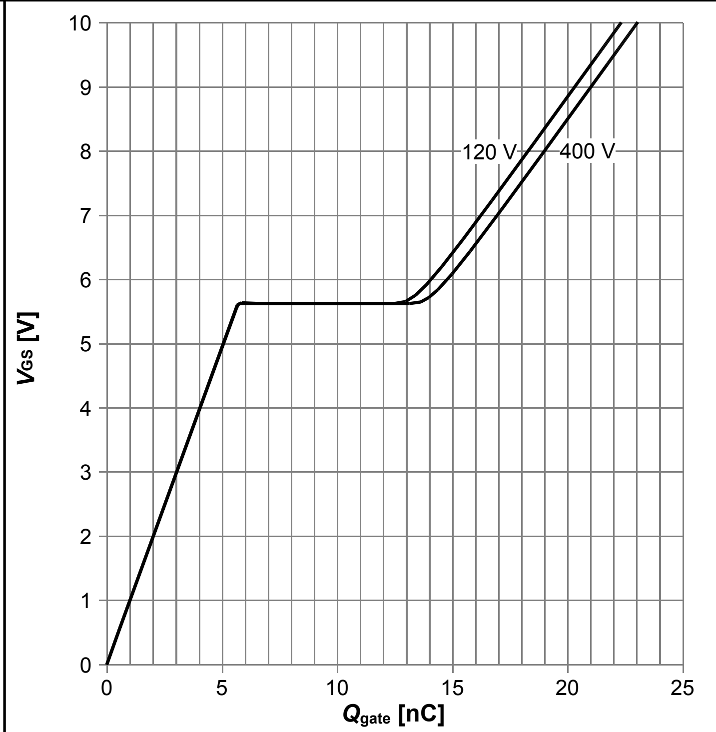
$R_{DS(on)}$=f(T_j); I_D=4.9 A; V_{GS}=10 V

Diagram 9: Typ. transfer characteristics



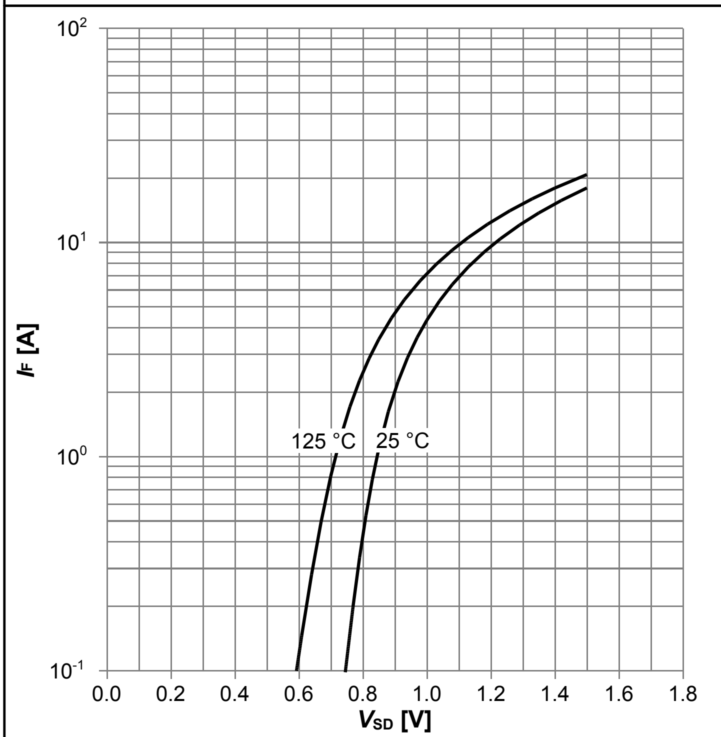
I_D=f(V_{GS}); V_{DS}=20V; parameter: T_j

Diagram 10: Typ. gate charge



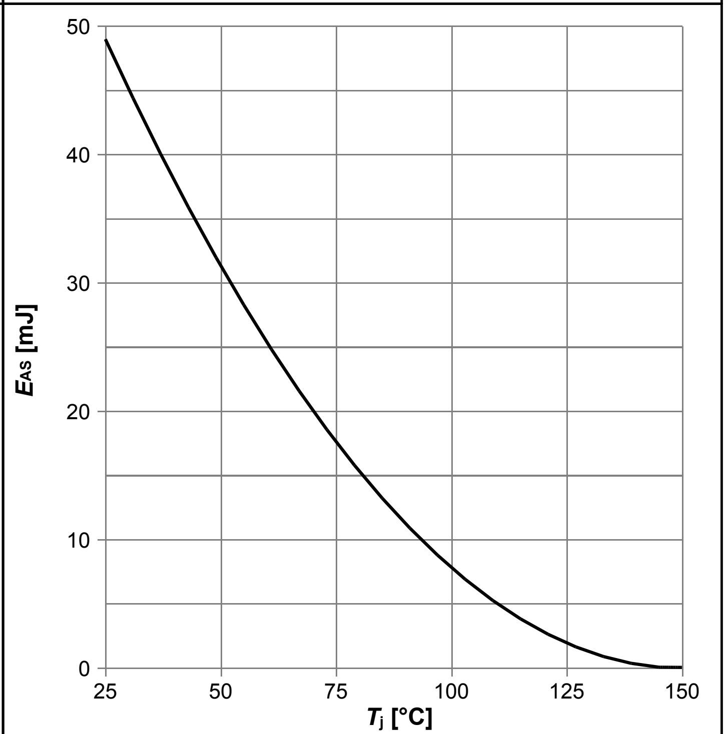
V_{GS}=f(Q_{gate}); I_D=4.9 A pulsed; parameter: V_{DD}

Diagram 11: Forward characteristics of reverse diode



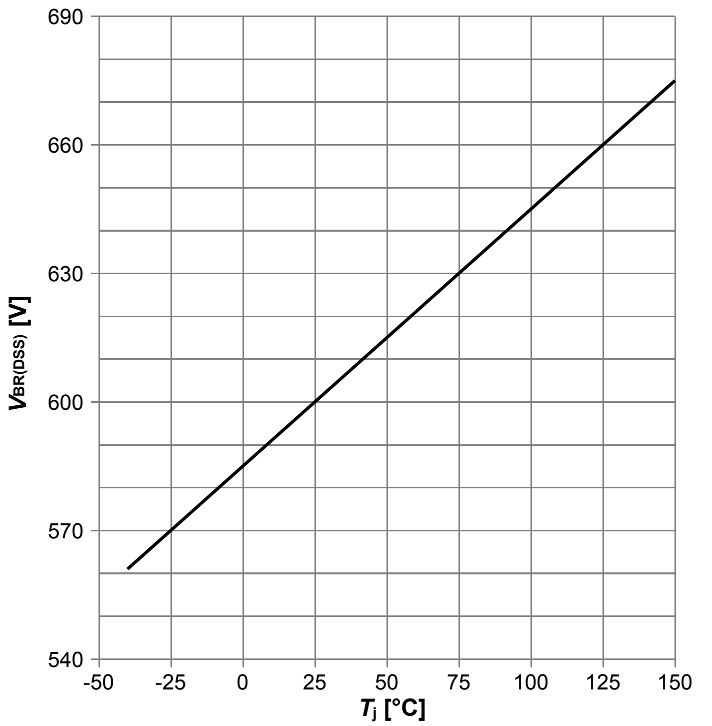
I_F=f(V_{SD}); parameter: T_j

Diagram 12: Avalanche energy



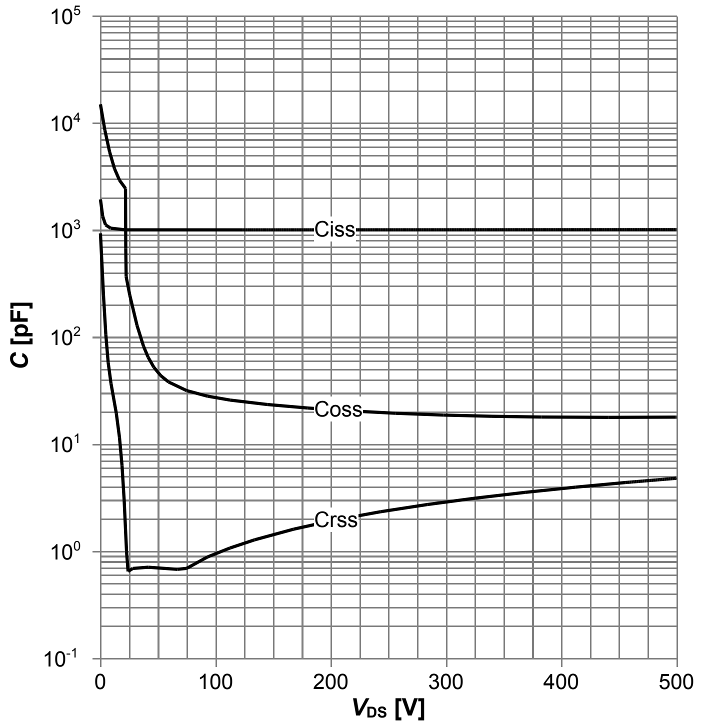
E_{AS}=f(T_j); I_D=3.2 A; V_{DD}=50 V

Diagram 13: Drain-source breakdown voltage



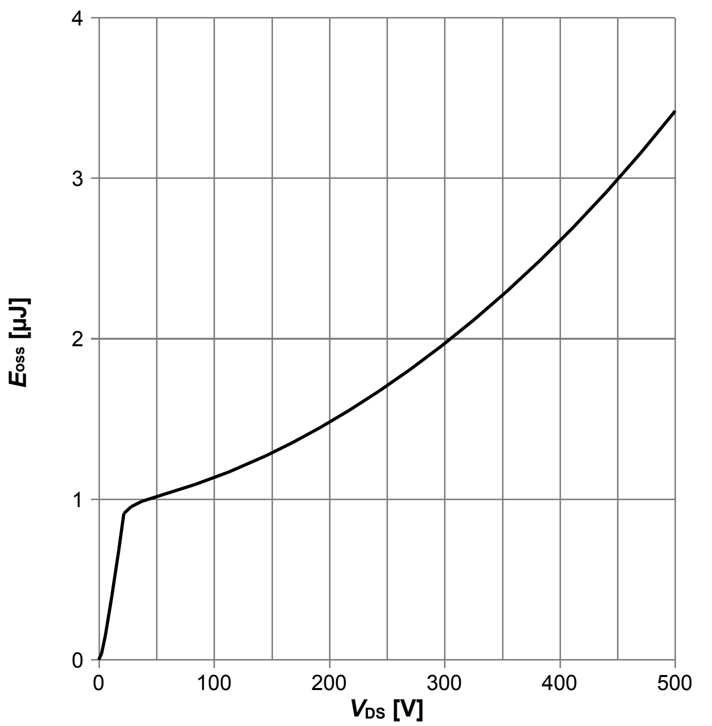
$V_{BR(DSS)}$=f(T_j); I_D=1 mA

Diagram 14: Typ. capacitances



C=f(V_{DS}); V_{GS}=0 V; f=250 kHz

Diagram 15: Typ. Coss stored energy



E_{oss}=f(V_{DS})

5 Test Circuits

Table 8 Diode characteristics

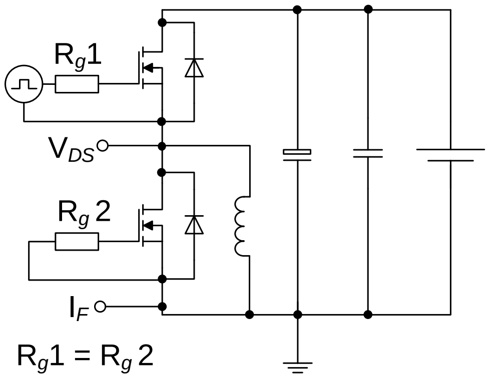
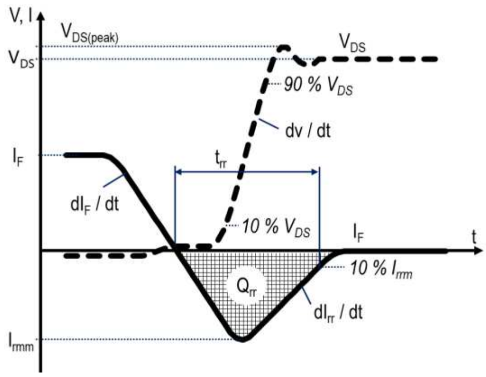
Test circuit for diode characteristics	Diode recovery waveform
	

Table 9 Switching times

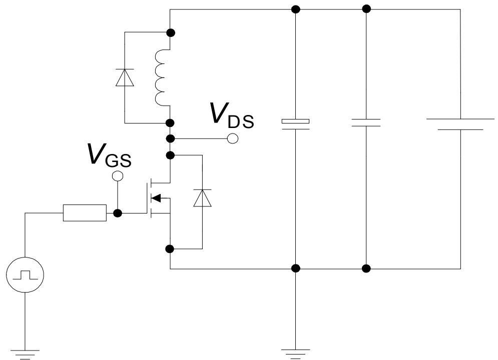
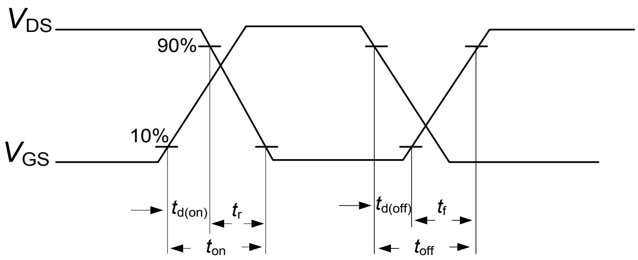
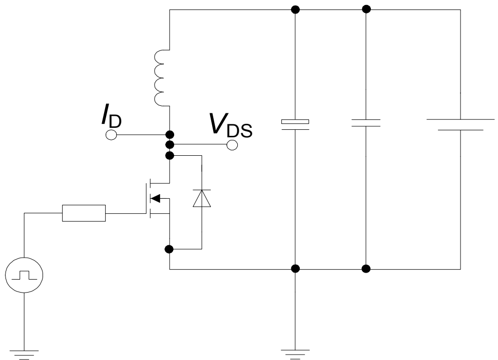
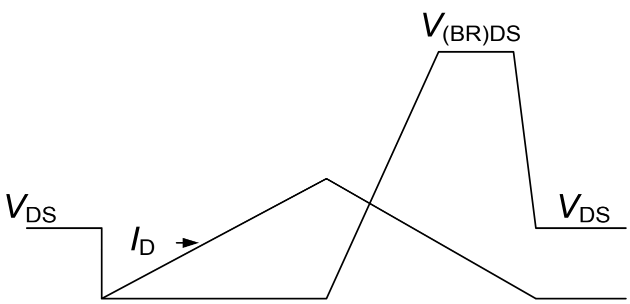
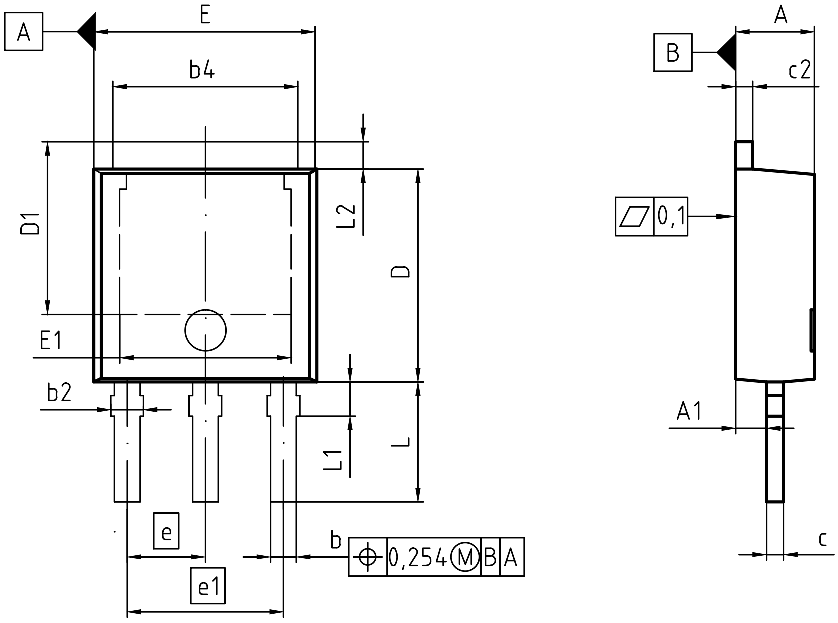
Switching times test circuit for inductive load	Switching times waveform
	

Table 10 Unclamped inductive load

Unclamped inductive load test circuit	Unclamped inductive waveform
	

6 Package Outlines



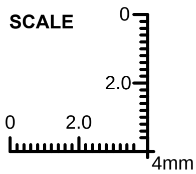
NOTES:

1. STANDARD QUALITY GRADE
2. ALL DIMENSIONS REFER TO JEDEC STANDARD TO-251 DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

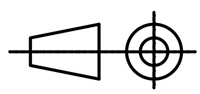
DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.20	2.40	0.087	0.094
A1	0.90	1.14	0.035	0.045
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b4	5.20	5.50	0.205	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.60	0.018	0.024
D	5.98	6.22	0.235	0.245
D1	5.00	5.60	0.197	0.220
E	6.35	6.73	0.250	0.265
E1	4.63	5.21	0.182	0.205
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
L	3.30	3.60	0.130	0.142
L1	0.85	1.25	0.033	0.049
L2	0.88	1.28	0.035	0.050

DOCUMENT NO.
Z8B00181052

SCALE



EUROPEAN PROJECTION



ISSUE DATE
06-04-2016

REVISION
01

Figure 1 Outline PG-TO 251-3, dimensions in mm/inches

7 Appendix A

Table 11 Related Links

- **IFX CoolMOS PFD7 Webpage:** www.infineon.com
- **IFX CoolMOS PFD7 application note:** www.infineon.com
- **IFX CoolMOS PFD7 simulation model:** www.infineon.com
- **IFX Design tools:** www.infineon.com

Revision History

IPS60R210PFD7S

Revision: 2019-04-09, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2019-04-09	Release of final version

Trademarks

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